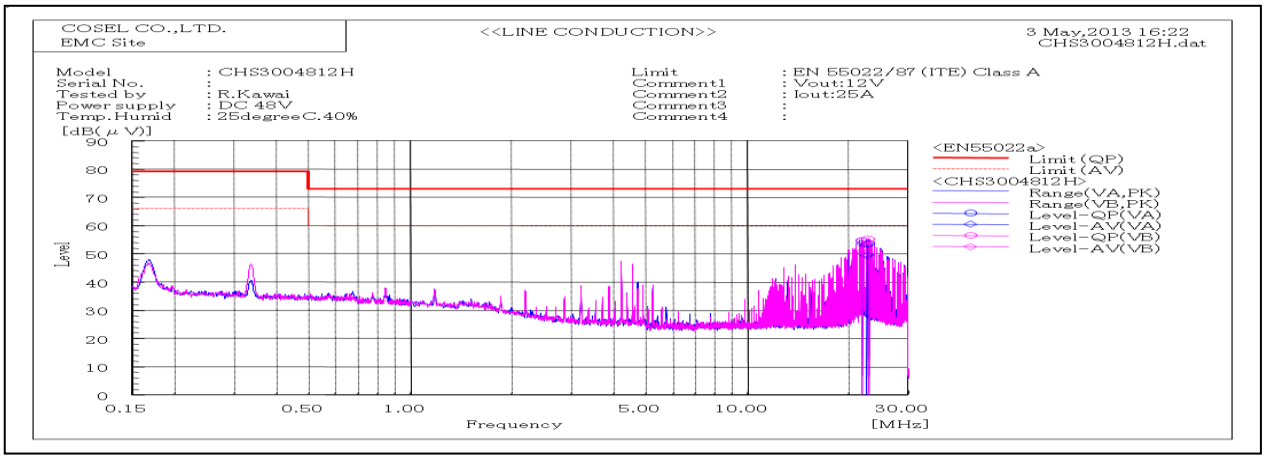
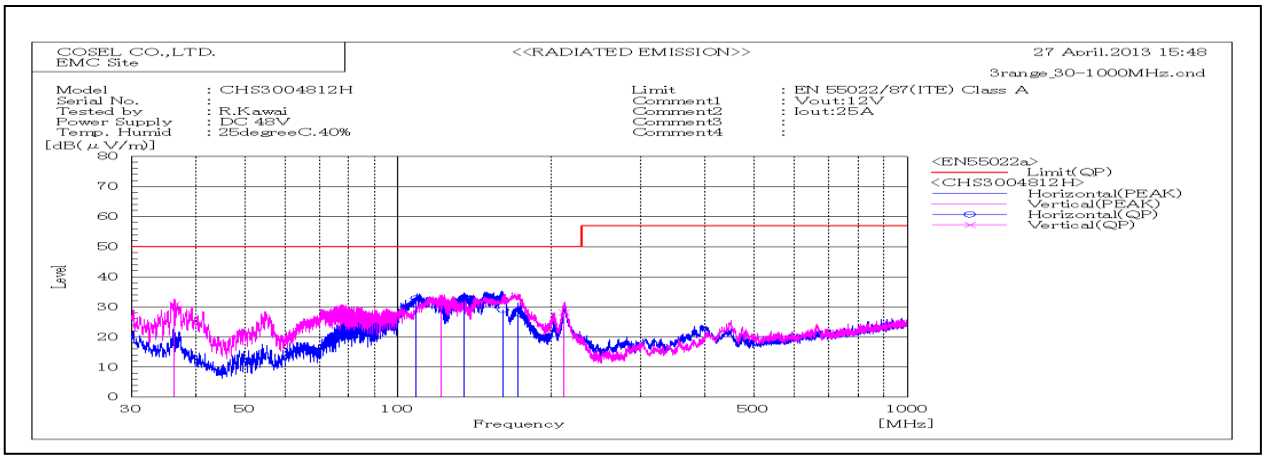
参考資料

DATA SHEET		Date	10-Jun-13
Model	CHS3004812H	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
21.8693		VA	33.6	32.6	21	54.6	53.6	73	60	18.4	6.4	Pass	
21.8621		VB	33.7	29.8	20.9	54.6	50.7	73	60	18.4	9.3	Pass	
22.5445		VA	32.4	28.4	21	53.4	49.4	73	60	19.6	10.6	Pass	
22.894		VA	32.6	28.5	21	53.6	49.5	73	60	19.4	10.5	Pass	
22.89025		VB	34.2	33.1	20.9	55.1	54	73	60	17.9	6	Pass	

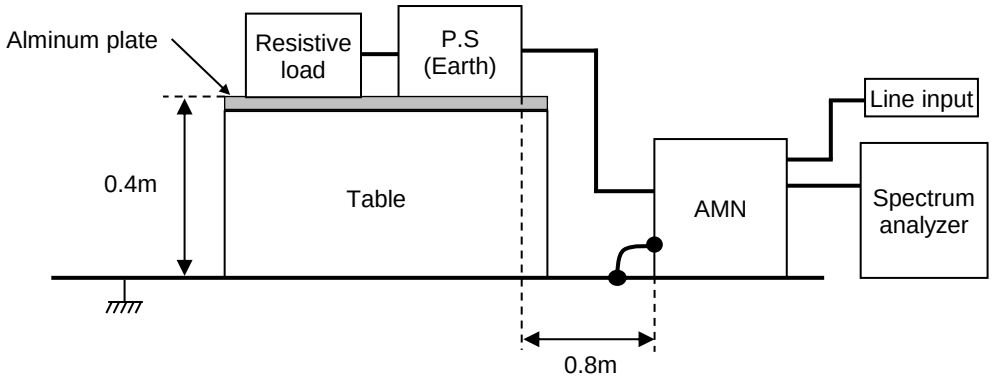


Frequency MHz	Polarization	Stability	Reading dB(uV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP		QP	QP	QP				
36.36	V	Stable	46	-15.2	30.8	50	19.2	Pass	106	159	
108.539	H	Stable	53.4	-20.5	32.9	50	17.1	Pass	150	227	
121.459	V	Stable	49.1	-17	32.1	50	17.9	Pass	147	127	
134.715	H	Stable	53	-19.9	33.1	50	16.9	Pass	150	246	
160.572	H	Stable	50.2	-21.1	29.1	50	20.9	Pass	159	345	
172.307	H	Stable	49.9	-22.1	27.8	50	22.2	Pass	153	246	
211.948	V	Stable	43.7	-15.6	28.1	50	21.9	Pass	140	330	

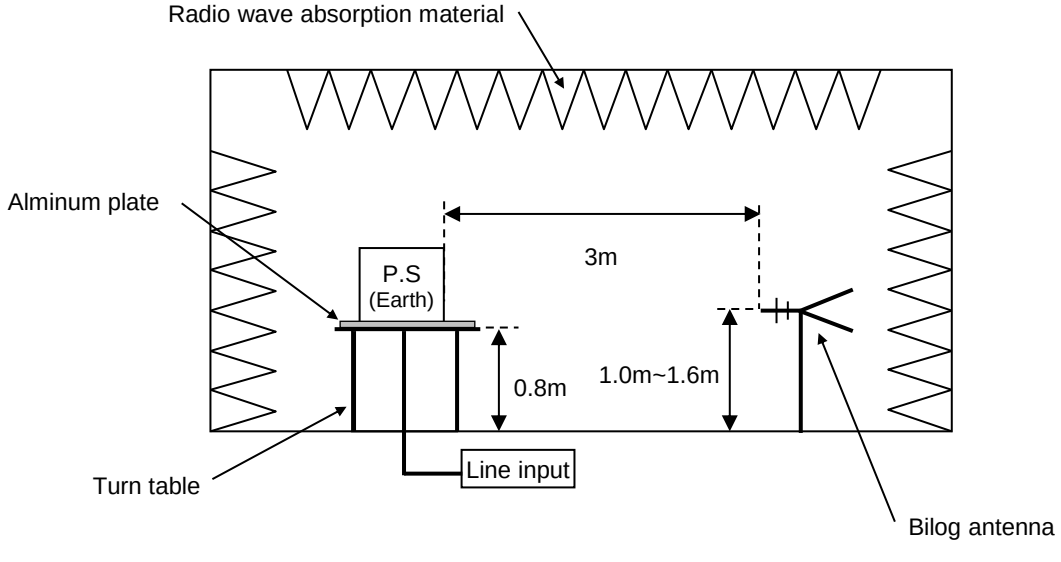
COSEL

DATA SHEET		Date	10-Jun-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai

1. Line conduction



2. Radiated emission

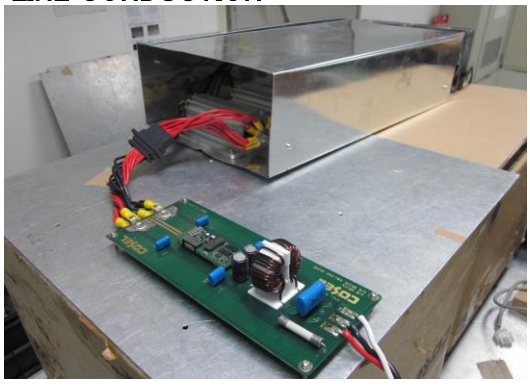


Conditions

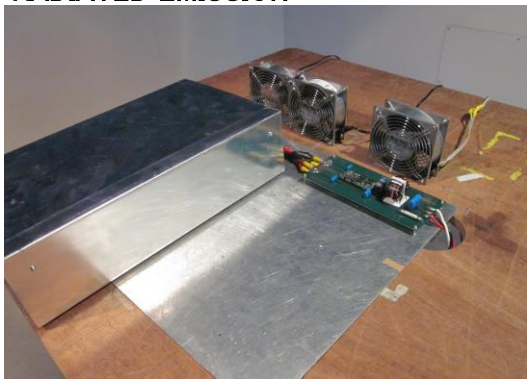
Test : EMI
Model Name : CHS30048□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

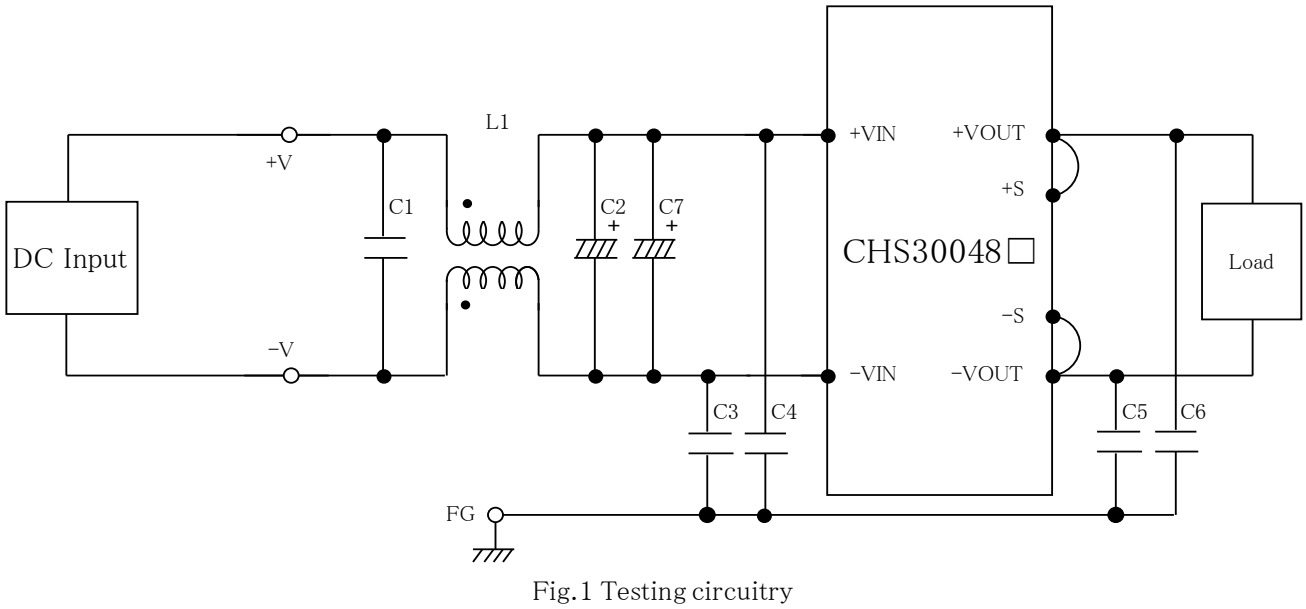


Fig.1 Testing circuitry

L1 : 1mH SC-15-10J (TOKIN)
C1 : 250V 2.2μF FPD22E225J4 (NITSUKO)
C2,C7 : 100V 100μF PWseries (nichicon)
C3,C4 : 630V 0.068μF FPD22J683J4 (NITSUKO)
C5,C6 : 630V 0.033μF FPD22J333J4 (NITSUKO)